

# PixFEL

## WP2: Building blocks

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## Tasks

Design of the fundamental building blocks for the readout of a pixel detector

- Development of individual stages
- Integration of building blocks in a single tier  $8 \times 8$  matrix
- Design of a  $32 \times 32$  single tier matrix to be interconnected to pixel sensor

## Milestones

2014

- Specification of the X-ray imager
- Design of test structures with single blocks (CSA with signal compression, SAR ADC, circuits for gain calibration, single MOS capacitors)<sup>1</sup>
- Design of a  $8 \times 8$  pixel matrix, with a  $100 \mu\text{m}$  pitch with simple readout electronics (no data storage in-pixel)<sup>1</sup>

2015

- Characterization of the test structures submitted in the first year runs
- Design of a  $32 \times 32$  chip with  $100 \mu\text{m}$  pitch ( $4.5 \mu\text{m} \times 4.5 \mu\text{m}$ )

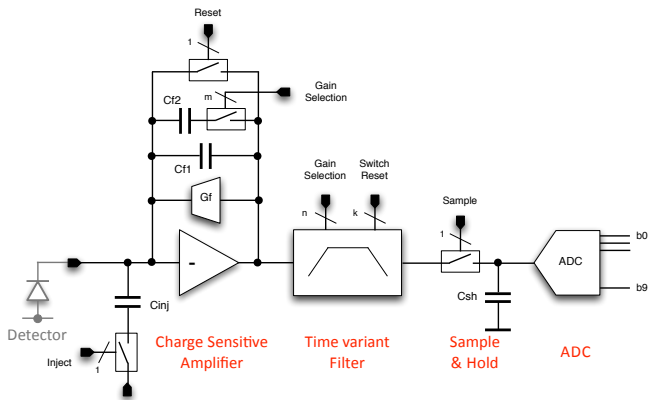
2016

- Test of the  $32 \times 32$  readout chip
- Interconnection and tests of the  $32 \times 32$  readout chip to a pixel sensor

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<sup>1</sup> $1920 \mu\text{m} \times 1920 \mu\text{m}$  chip, through Europractice with the mini@sic option, 65 nm CMOS technology

# Readout channel block diagram

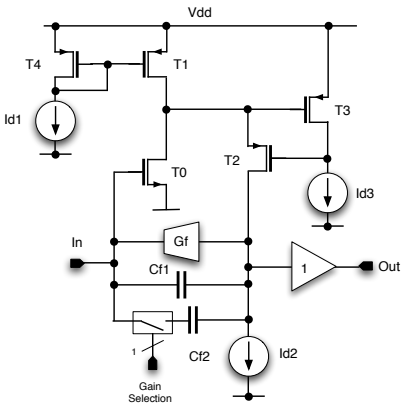
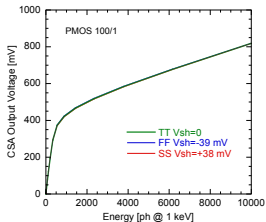
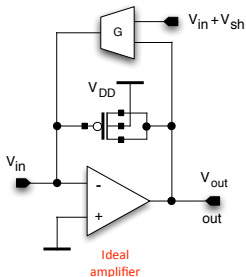


The analog channel consists of

- **Charge-sensitive preamplifier** with signal compression
- **Time-variant filter** with gain and integration time selection options
- **Sample & Hold**
- **Analog-to-Digital conversion** performed by a 9-10 bit SAR ADC
- **Sequencer** for fast signals generation (switch, reset, injection,...)

# Charge sensitive amplifier with signal compression

Use the non-linear features of MOSFET capacitors to dynamically change the gain with the input signal amplitude



## Amplifier architecture:

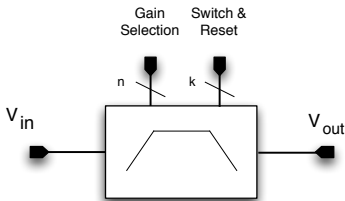
active folded cascode (with local feedback)  
loaded by an active cascoded load and  
output stage

In the case of events with a known repetition rate, time variant shaping may provide some advantage with respect to continuous time processing

- Reduced time to return to base
- May be designed in such a way to provide the sample to ADC at its output

## Trapezoidal weighting function

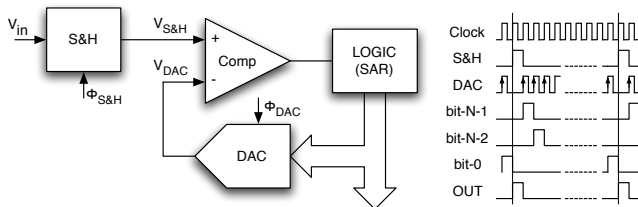
- Gated integrator
- Correlated Double Sampling (CDS)



## To be investigated

- Time-invariant filter (RC-CR or CR-RC<sup>2</sup>)
- RC-CR shaper with gated integrator
- Multiple Correlated Double Sampling (MCDS)
- Rail-to-rail output stage

Based on a successive approximation register (SAR) architecture



## Specifications

- resolution: 9-10 bits  $\Rightarrow$  guarantees single photon resolution at small signal, small quantization noise in Poisson-limited regime
- sampling rate: 5 MS/s  $\Rightarrow$  for operation at the Eu-XFEL
- area:  $< 5000 \mu\text{m}^2$

## Readout options

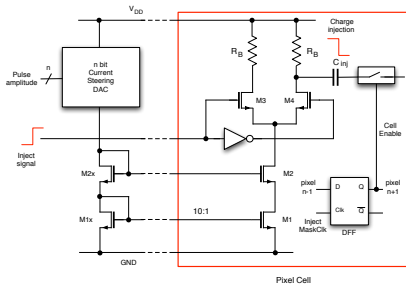
- Parallel conversion and readout
- Independent conversion and readout

Programmable signal generator circuit integrated in each pixel for gain calibration

The proposed circuit consists of two main parts

- The **Digital-to-Analog Converter** located in the matrix chip periphery
- The **Pulsar** to be included in the pixel cell

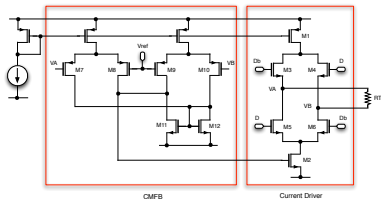
The current provided by the DAC is mirrored into each pixel, where the pulser injects a charge directly into the input of the amplifier by applying a voltage step to a small injection capacitor



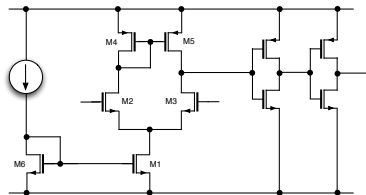
The granularity of the generated signal amplitude should be chosen to provide a significant number of experimental points also in the high gain portion of the input-output front-end curve and not to exceed the ADC resolution

**I/O circuits** to transfer data off-chip and to feed the clock to the ADC, the time variant shaper, the memory and the readout circuits

**CMOS to LVDS converter**



**LVDS to CMOS converter**



**Power supply/temperature independent band-gap reference circuits** to provide stable voltage references to in-pixel blocks (e.g., the ADC).



## Configuration in Pavia

<b>Cadence</b>	cadence_6.16.010
<b>Calibre</b>	ixl_cal_2010.2.13.12
<b>MMSIM</b>	MMSIM_12.11.164
<b>IMEC DK</b>	T-N65-CM-SP-007-K3 (Cadence 0A PDK 1.7A) T-N65-CM-SP-007-K4 (PATCH)
<b>Files</b>	t-n65-cm-sp-007-k3_1.7a_20120927.zip tn65cmsp007k4-1.7a-1.zip t-n65-cm-sp-007-x1_1.5a.zip t-n65-cl-dr-001_2.2_20130829[1].zip
<b>Settings</b>	Select process : RF Select voltage : 1.2V / 2.5V / 2.5V under-drive 1.8V / 2.5V over-drive 3.3V Select MiM cap : MIM_2.0fF Select metal option : 1p9m_6X1Z1U_ALRDL *ind_1z1u *Star_RC *Cal_RC *QRC

Collect this data and try to agree on common versions